Two-dimensional BiTeX Crystal with Persistent Luminescence

Induced by Photochemical Reaction

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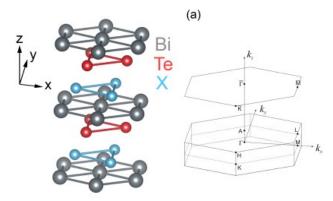


Figure S1. BiTeX (X = Cl, Br, I) is a layered van der Waals material in which Te layers, Bi layers, and X layers are alternately stacked along the c-axis direction.

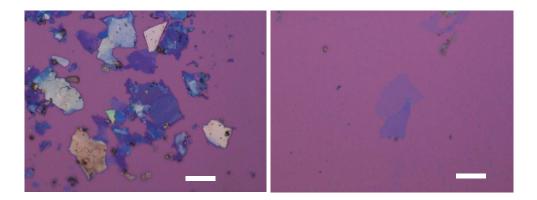


Figure S2. BiTeI (left) and BiTeCl (right) nanosheets on SiO_2/Si substrate under optical microscope, with inset scale bar 20 um and 10 um, respectively.

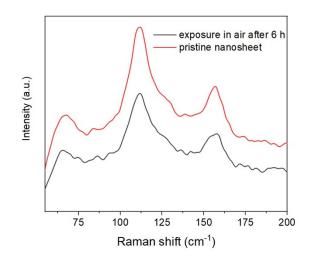


Figure S3. The stability of BiTeBr nanosheet characterized by Raman spectra.

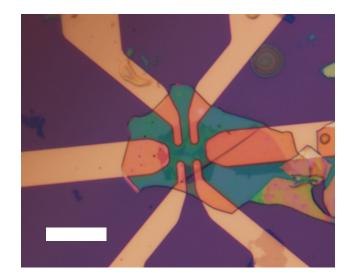


Figure S4. The nanodevice images of BiTeBr nanosheets with BN capped. The inset scale bar is 20 um.

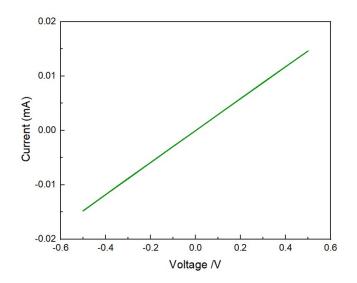


Figure S5. I-V curves of BiTeBr nanosheets nanodevice test with two electrodes.

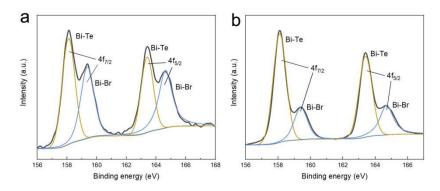


Figure S6. The XPS analysis of Bi 4f peak for BiTeBr nanosheet (a) before and (b) after UV light irradiation.

Element	wt%	atomic ratio
0	4.51	30.12
Br	14.18	18.97
Te	28.62	23.97
Bi	52.69	26.94
total	100.00	100.00

Table 1. Atomic ratios for BiTeBr nanosheet under EDS mapping of TEM.